

BRUKER WEBINAR WITH DRAGONFLY ENERGY CORP.

Element Mapping (EDS) for the Optimization of Battery Materials and Processes

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Outline



EDS analysis for detecting and identifying contaminants in Cathode and Anode

3 Conclusions

Question & Answer session



01

EDS and multi-model analytical applications in Battery Cell R&D

Innovation with Integrity



Revolutionizing Green Energy Storage.

EDS Applications in Battery Cell R&D

Presenter:

Emily Litt, Research & Development Scientist & Group Lead



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DRAGONFLY ENERGY

Comprehensive Lithium Battery Company

- Proven Market Penetration Through Battle Born Batteries Product Line
- Strong Vision for Future Domestic Cell Production and Technology









THE TEAM

Denis Phares, Ph.D Chief Executive Officer

30+ years of experience in the fields of Energy, Nanotechnology, Fluid Mechanics, and powder processing

- B.S. in Physics from Villanova University
- M.S. and Ph.D in Environmental Engineering Science from California Institution of Technology
- MBA from the University of Nevada, Reno



Vick Singh, Ph.D

Director of Research and Development

- 10+ years of experience in various research functions within private & public sector firms
- Postdoctoral Research Fellow at the Lawrence Livermore National Laboratory's Center for Global Security Research
- B.S. in Chemical Engineering from the University of Tennessee, Knoxville
- Ph.D in Materials Science & Engineering from the University of Nevada, Reno



Emily Litt

Research & Development Scientist & Group Lead

- B.S. in Material Science and Engineering from the University of Nevada, Reno
- Leads team in systematic development of innovative methods to enhance lithium-ion batteries
- Conducts electrochemical experiments and materials analysis, aiming to optimize battery performance and efficiency

15+ Engineers and Scientists Supporting Research Efforts



Dragonfly Energy's approach to energy technology development can be described in one word:

Comprehensive

CAUTION!

Fundamental Materials And Processes

BRAUN

Product Deployment (DTC & OEM)

UKA (5. (2.)

Energy Technology Ecosystem Supply Chain Readiness

dragonfly

Cell and Formation Prototyping

dragonfly "

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How are Lithium-ion Batteries Made?





Lithium Iron Phosphate Cathode



Graphite Anode



What's the current status of lithium-ion?



dragonfly

FUNDAMENTAL MATERIALS AND PROCESSES

- □ Founded as a manufacturing technology company in 2012
- Applying sustainable manufacturing processes to current and next-generation cell chemistries





FUNDAMENTAL MATERIALS AND PROCESSES

- □ Fundamental Capabilities:
 - □ Infrastructure
 - +\$15 million investment with Bruker and Tescan for scientific instruments
 - □ Highly-Skilled R&D Team and Thrust Areas
 - □ Battery Cell Science
 - Manufacturing Innovation
 - Materials Characterization
 - Data Science





Streamlined Cell Manufacturing & Battery Pack Assembly

Optimization of Manufacturing Processes

- □ Extensive Automation Experience
- Designed & Built in House
- Cost Effective

Dry Room

□ Coming Soon for Conventional and Solid-State Cell Prototyping

Decreased Manufacturing Footprint

Up to 150 MWh in Cell Production Capacity via Pilot Line







Powders

- Coating
- Composition
- □ Homogeneity & Distribution











ANODE ANALYSIS

- General Construction & Quality
- Post-Mortem Analysis
- Interface Investigation





CATHODE ANALYSIS

- General Construction & Quality
- Post-Mortem Analysis
- □ Interface Investigation





SOLID STATE ANALYSIS

- Electrolyte Wetting
- Homogeneity & Distribution
- Speciation Using EDS
- Interface Investigation











ADVANCED TECHNIQUES

□ High Resolution Elemental Mapping

Complementary Multimodal Techniques





Dragonfly is Positioned to Sit at the Nexus of Energy Technology





Displacing Lead Acid Today, Replacing Coal Tomorrow



Thank You

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EDS analysis for identifying and detecting contaminants in cathode and anode

Innovation with Integrity

Outline



- Introduction of investigated samples and materials
- Introduction to EDS what signal is being measured, how to interpret, what questions can be answered
- Measurement conditions
 - Choice of acceleration voltage and SEM parameters
- Results of anode and cathode material
- Introduction and comparison of EDS detectors of conventional geometry and Bruker FlatQUAD
- Detection limit of EDS: How can very low concentration contamination be detected and located?
- Comparison of anode/cathode results with EDS detectors of conventional geometry and Bruker FlatQUAD



Investigated samples



Anode sample: graphite on copper (pristine, not cycled)





Cathode sample: LiPO4 on aluminum (pristine, not cycled)







What is EDS and what questions can it answer?

- Element detection based on X-ray emitted due to the excitation of primary electron beam of a scanning electron microscope
- How is element distribution interpreted?
- What elements are in the sample?
- How are they distributed? (-> where do they originate from in the battery manufacturing/cycling/life process)
- In what quantity are these elements present in the sample?
- What is the lowest amount of material EDS can detect?

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Introduction to EDS – what signal is being measured





Introduction to EDS – how mapping works





Measurement key points

- Samples: Manufactured electrode tapes:
 - Pristine Anode: Copper foil coated with carbon on a single side.
 - Pristine Cathode: Aluminum foil coated with LiFePO4 on a single side.
- Sample preparation: Samples mounted on carbon tape. Mechanical cut for crossection
 The samples are stable in room conditions, no glovebox or inert gas transfer was necessary
- EDS /SEM Measurement conditions:

high vacuum SEM conditions. No low vacuum/variable pressure needed

- EDS setup: Choice of acceleration voltage: 12 or 15kV is sufficient to cover all elements
 - Lower kV: minimizing interaction volume-> maximizing spatial resolution. (not necessary)
 - Higher kV: access K-Lines of heavier elements (not necessary as deconvolution works fine)

Graphite ANODE - top overview





Analysis parameters

Detector	XFlash® 760
High voltage	15 kV
Magnification	250
Beam current	~5 nA
Mapping time	12 min
Input count rate (ICR)	92 kcps



Graphite ANODE - top overview





Element identification – how to find all elements



Elements identified by deconvolution of sum spectrum.

Element maps are visualized based on the deconvolved net coutns



Element identification – presence of Sr or is it Si?

Are the Sr maps only the misinterpretation of Si due to the peak overlap?

15kV measurements: only Sr-L lines available which overlap with Si-K! Sr-K lines at 14-15kV are not excited



Deconvolution with Si only -> "bad match"



Deconvolution with Si and Sr: Good match! Peakform of a pure Si-particle:





Element identification – presence of Sr or is it Si?

Are the Sr counts only the misinterpretation of Si?

25kV measurements: Sr-K lines properly excited and present





Sr L-line map 15kV XFlash760 30 minutes Sr K-line map 25kV XFlash760 13 minutes

Ch 1

Si Sr

Very low Sr-L signal!-> longer measurement needed

Sr K- line map **25kV** XFlash760 90 minutes

Bruker Nano Analytics, Berlin, Germany



Element identification – this particle contains also Ba

Ba-peak present in extracted spectrum of single particle!



Do the math:

quantification of particle spectrum and dividing with area coverage: 3w% Ba * 3% area coverage * 1% area coverage of original map:

= 9*10E-6

-> ppm sensitivity!



How to get the most information the fastest – use FlatQUAD for better detection





Better view of sample topography Less absorption of X-ray signal x15-30 more X-ray signal: less measurement time needed

Bruker XFlash® FlatQUAD EDS detector Features and advantages





- Annular 4-segment (4x) SDD geometry, central ap.
- Side entry EDS (STEM/BSE like)
- Large solid angle of 1.1 sr
- High take-off angle (~60°)
- Optimal signal collection geometry

XFlash ® FlatQUAD



- High sensitivity at very low probe currents ~few pA
- Minimize sample charging/damage/C-deposition at low PC
- High vacuum conditions EDS high resolution
- Low vacuum capability
- Moderate probe currents for high-speed EDS mapping
- Low x-ray yield samples: Low PC High resolution
- Nanoparticles, Thin lamellae, beam sensitive materials

ANODE - cross section: comparison of conventional detector and FlatQUAD





Analysis parameters

Detector	XFlash® 760	XFlash® FlatQUAD
High voltage	12 kV	12 kV
Beam current	~1nA	~1nA
Mapping time	30 min	30 min
Input count rate (ICR)	19,5 kcps	667 kcps
Total counts in map	2.7 x10⁷	8.2 x10 ⁸







ANODE crossection – XFlash® 760 vs FlatQUAD





ANODE crossection – XFlash® 760 vs FlatQUAD







ANODE crossection – XFlash® 760 vs FlatQUAD: finding "hiding elements": S, Cr







Noisier maps, Shadowed areas



Less noise in maps, Access to areas with high topography

ANODE crossection – XFlash® 760 vs FlatQUAD: finding "hiding elements": Ca









Noisier maps, Shadowed areas

XFlash® 760



Less noise in maps, Access to deeper /shadowed areas

XFlash® FlatQUAD

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ANODE crossection – XFlash® 760 vs FlatQUAD: finding "hiding elements": Ti







Elements identified by deconvolution of sum spectrum: No Ti found Ti is below detection level!





Elements identified by deconvolution of MAXIMUM PIXEL SPECTRUM Ti identified

ANODE crossection – XFlash® 760 vs FlatQUAD: finding "hiding elements": Ti









Ti identified by deconvolution of MAXIMUM PIXEL SPECTRUM Ti is below detection level

Bruker Nano Analytics, Berlin, Germany



ANODE crossection – Ti: trace element below EDS detection limit





Do the math: Use AUTOPHASE function to calculate Area coverage= 0.01% Extract object spectrum of single particle: Local concentration of Ti: 85% -> 85 ppm Ti detected

Element	Line series	Mass Norm. [%]	Atom [%]	abs. error [mass%] (3 σ)
С	K	0,00	0,00	0,00
0	K	0,41	1,19	0,88
Na	K	1,07	2,18	0,54
Si	K	0,53	0,87	0,25
AI	К	1,59	2,75	0,41
CI	K	0,55	0,73	0,22
Ca	К	4,41	5,13	0,84
к	K	0,71	0,84	0,26
Cr	K	0,80	0,72	0,72
Ti	K	85,35	83,26	14,70
Nb	L	4,58	2,30	0,77
		100,00	100,00	

Nb also identified in the particles!

Area coverage= 0.01% Extract object spectrum of single particle:

Local concentration of Nb: ~5% -> presence of Nb on the concentration level of 5ppm detected!

Detected main elements and contaminants – Graphite anode material on Cu



Element	Coexist with	Detection with EDS	Detection at 12/15kV	Origin	Comment
Na		easy	K-line	Polymer binder	Assists in mapping polymer distribution.
Cu		easy	K-line	Anode substrate	
Si	Partly with Sr	easy	K-line	Contaminant	Common contaminant in anode manufacturing.
AI		easy	K-line	Contaminant	Common contaminant in anode manufacturing.
Fe, Cr, Ni		Low signal	K-line	Contaminant	Common contaminant in anode manufacturing.
Р		Low signal, could be found with 760	K-line	Contaminant	Common contaminant in anode manufacturing.
CI		easy	K-line	Contaminant	Common contaminant
S		easy	K-line	Contaminant	Common contaminant
Ti		Better with FQ Found with MaxPix	K-line	Contaminant	Common contaminant in anode manufacturing.
К		easy	K-line	Contaminant	Common contaminant
Sr	S, Ba?	Better with FQ	L-line + doublecheck with K-Line @25kV	Contaminant	Sr-sulphate?
Ba	Sr, S	Hard to find. ppm	L-line	Contaminant	?
Nb	Ti	Hard to find. ppm	L-line	Contaminant	?

Main elements and contaminants – LiPO4 cathode material on Aluminium



Element	Coexist with	Detection with EDS	Origin	Comment
Fe		easy	Cathode	LiFePO4
0		easy	Cathode	LiFeP04
Ρ		easy	Cathode	LiFeP04
C		easy	Cathode/Contaminant	Carbon is added to cathodes, however graphite may be occosionally viewed in cathodes as a contaminant from manufacturing.
AI		easy	Current Collector	Aluminum comes from current collector.
Ті		easy	Contaminant	Common contaminant in cathode manufacturing.
Na	Partly with Cl	easy	Contaminant	Common contaminant in cathode manufacturing.
CI	Partly with Na	easy	Contaminant	Common contaminant in cathode manufacturing.
Si		easy	Contaminant	Common contaminant in cathode manufacturing.
Са		easy	Contaminant	Common contaminant in cathode manufacturing.
К		easy	Contaminant	Common contaminant in cathode manufacturing.
S	Partly with Sr	easy	Contaminant	Common contaminant in cathode manufacturing.
Cu		easy	Contaminant	Common contaminant in cathode manufacturing.
Cr	Ni	with MaxPixSpectrum	Contaminant	Common contaminant in cathode manufacturing.
Ni	Cr	with MaxPixSpectrum	Contaminant	Common contaminant in cathode manufacturing.
Sr			Contaminant	
V		FlatQUAD; with MaxPixSpectrum	Contaminant	



CATHODE - Top view with FlatQUAD



Analysis parameters

Detector	FlatQUAD
High voltage	12 kV
Beam current	~0,5 nA
Input count rate (ICR)	640 kcps
Total counts (per map)	7x10 ⁷
Mapping time	3 min



XFlash® FlatQUAD



CATHODE - Top view with FlatQUAD





ciement	AL. NO.	series	[%]	[%]	[mass%] (3 σ)
с	6	к	6,02	19,63	2,40
P	15	к	24,35	30,79	6,66
v	23	к	11,43	8,79	4,78
Fe	26	к	58,19	40,80	25,64
			100,00	100,00	



Area coverage= 0.01% Local concentration of V: 11% -> 11 ppm Ti detected within 3 minutes of measurement time!

XFlash® FlatQUAD

Summary

- Introduction to EDS what signal is being measured, how to interpret, what questions can be answered
- Measurement conditions
 - Choice of acceleration voltage and SEM parameters
- Results of anode and cathode material in top and side view
- Introduction and comparison of EDS detectors of conventional geometry and Bruker FlatQUAD
- Detection limit of EDS: How can very low concentration contamination be detected and visualized?
- Comparison of results of EDS detectors of conventional geometry and Bruker FlatQUAD
 - Shorter measurement times for trace element detection
 - No shadowing effect (easier localization of hiding elements on samples with rough topography)



03 Conclusions

Innovation with Integrity



04 Questions & Answers

please type your questions in the Q&A window and press SEND

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Thank you!



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